

Features

- GEN3 Hexfred Technology
- Low V_F
- Low I_{RR}
- Low t_{RR}
- Soft Reverse Recovery

Benefits

- Benchmark Efficiency for Motor Control Applications
- Rugged Transient Performance
- Low EMI
- Excellent Current Sharing in Parallel Operation

1200V
 $I_{F(nom)} = 75A$
 $V_{F(typ)} = 1.75V @ I_{F(nom)} @ 25^\circ C$
 Motor Control Antiparallel Diode
 125mm Wafer

Electrical Characteristics (Wafer Form)

Parameter	Description	Guaranteed (min, max)	Test Conditions
V_F	Forward Voltage Drop	0.99V min, 1.31V max	$I_F = 10A, T_J = 25^\circ C$
BV_R	Reverse Breakdown Voltage	1200V min	$T_J = 25^\circ C, I_R = 500\mu A$
I_{RM}	Reverse Leakage Current	30 μA max	$T_J = 25^\circ C, V_R = 1200V$

Mechanical Data

Nominal Backmetal Composition, (Thickness)	Cr- Ni - Ag, (1kA - 4kA - 6kA)
Nominal Front Metal Composition, (Thickness)	99% Al/1% Si, (3 μm)
Dimensions	0.234" x 0.443"
Wafer Diameter	125mm, with std. < 100 > flat
Wafer Thickness, Tolerance	310 μm , +/-15 μm
Relevant Die Mechanical Dwg. Number	01-5364
Minimum Street Width	100 μm
Reject Ink Dot Size	0.25mm diameter minimum
Ink Dot Location	Consistent throughout same wafer lot
Recommended Storage Environment	Store in original container, in dessicated nitrogen, with no contamination
Recommended Die Attach Conditions	For optimum electrical results, die attach temperature should not exceed 300 $^\circ C$

Die Outline

NOTES:

1. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
2. CONTROLLING DIMENSION: [INCH].
3. DIMENSIONAL TOLERANCES:

BONDING PADS:	< 0.635 TOLERANCE = +/- 0.013
WMDTH	< [.0250] TOLERANCE = +/- [.0005]
&	> 0.635 TOLERANCE = +/- 0.025
LENGTH	> [.0250] TOLERANCE = +/- [.0010]
OVERALL DIE:	< 1.270 TOLERANCE = +/- 0.102
WMDTH	< [.050] TOLERANCE = +/- [.004]
&	> 1.270 TOLERANCE = +/- 0.203
LENGTH	> [.050] TOLERANCE = +/- [.008]

01-5364

Fig.1 - Typical Diode Recovery

$V_{CC}=600V$; $R_g=5\Omega$; $T_j=125^\circ C$;
 $L=200\mu H$; Driver=IRGC75B120KB

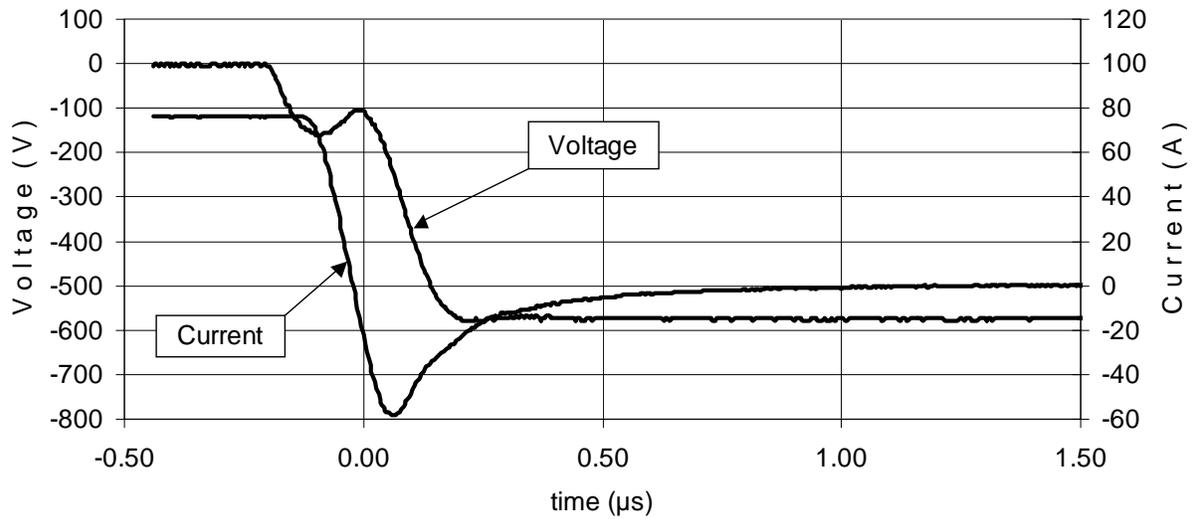


Fig.2 - Typical Diode Forward Characteristic
 $t_p=300\mu s$

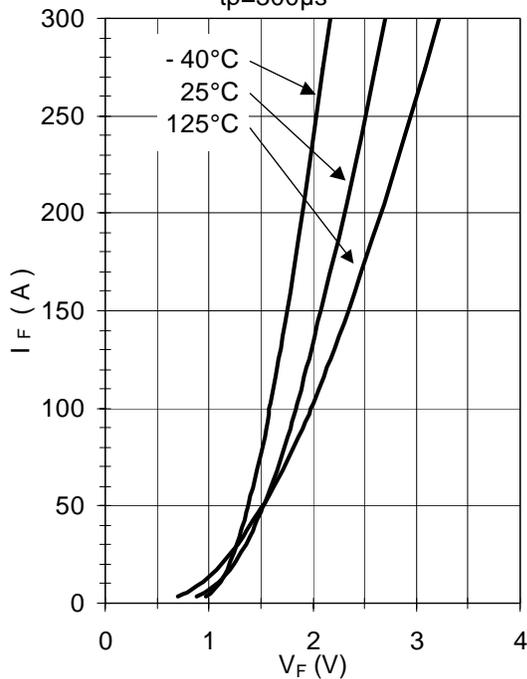


Fig. 3 - Diode Recovery Circuit

